PCN Number:		20141217001					PC	PCN Date:		12/18/2014									
Title:	Qualification	of A	mk	or Philippine	es as an <i>i</i>	Additional A	ssen	nbly Loc	ation f	or Se	lect Devices								
Customer Contact:		PCN Manager		Phone:	+1(214)480-6037		037	Dept:	Quality Services										
Proposed 1 st Ship Da		ite:	C	03/18/2015 Estimated Sample A		vailabi	IIIaniiitv'		provided request										
Change Type:																			
Assembly Site				Assembly Process			\boxtimes	Assembly Materials											
Design				Electrical Specification			Mechai	nical S	pecif	ication									
Test Site				Packing/Shipping/Labeling			Test Process												
Wafer Bump Site				Wafer Bump Material				Wafer Bump Process											
Wafer Fab Site				Wafer Fab Materials			Wafer Fab Process												
				Part number change															
					PCN De	etails					PCN Details								

Description of Change:

Texas Instruments is pleased to announce the qualification of Amkor Philippines as an additional Assembly location for the devices listed below. Device construction materials differences are noted in the table below:

	Stat	s ChipPAC K	orea	AP3			
Package	ZCU	zcQ	ZWD	ZCU	ZCQ	ZWD	
Mold compound	R003-0429C	R003-0429C	R003-0429C	1013422010	1013422010	1013422010	
Mount compound	R008-0023A	R008-0052A	R008-0023A	No change	101321630	No change	

Reason for Change:

Continuity of Supply. Stats ChipPAC Korea will no longer support TI production after June, 2015.

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Assembly Site		
STATS ChipPAC Korea	Assembly Site Origin (22L)	ASO: CPA
AMKOR Philippines	Assembly Site Origin (22L)	ASO: AP3

Sample product shipping label (not actual product label)



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ACO: MYS

Topside Device marking:

Assembly site code for CPA= 8 Assembly site code for AP3= 3

Product Affected								
SN0901052ZCU	TX517IZCQ	VSP2435ZWDR						

Qualification Plan - Estimated completion: February, 2015							
This qualification has been specifically developed for the validation of this change. The qualification data							
validates that the proposed change meets the applicable released technical specifications.							
Qualification Device: SN0901052ZCU (MSL3-260C)							
Package Construction Details							
Assembly Site:	AP3	Mold Compou	ınd:	1013422010			
# Pins-Designator, Family:	289-ZCU, nFBGA	Mount Compound:		R008-0023A			
Solder Ball Composition:	SnAgCu Bond V		/ire: 0.9 Mil Dia., Au				
Qualification: Plan Test Results							
Reliability Test	Conditions		Sample Size / Accept				
**Unbiased HAST	110C/85%RH/17.7 psis (264 Hours)		77/0				
**T/C -55C/125C	-55C/+125C (700 Cyc)			77/0			
Ball Bond Shear	76 balls, 3 units min		76/0				
Bond Pull	76 Wire, 3 units min		76/0				
Notes: **Tests require preconditioning sequence: MSL3-260C							

Qualification Plan - Estimated completion: February, 2015								
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.								
Qualification Device: TX517IZCQ (MSL 3-260C)								
Package Construction Details								
Assembly Site: AP3			Mold Compound: 101342		122010			
# Pins-Designator, Family: 144-Z		ZCQ, nFBGA Mount Compound:		101321630				
Solder Ball Composition: SnAg(Cu Bond Wire: 1.0 Mil Dia		ia., Au				
Qualification: Plan Test Results								
Reliability Test		Conditions		Sam	Sample Size / Fail			
				Lot 1	Lot 2	Lot 3		
**Unbiased HAST		110C/85%RH/17.7 psis (264 Hours)		77/0	77/0	77/0		
**T/C -55C/125C		-55C/+125C (700 Cyc)		77/0	77/0	77/0		
Ball Bond Shear		76 balls, 3 units min		76/0	76/0	76/0		
Bond Pull		76 balls, 3 units min 76/0 76/0			76/0			
Notes: **Tests require preconditioning sequence: MSL3-260C								

Qualification Plan - Estimated completion: June, 2015 This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. **Qualification Device: VSP2435ZWD** (MSL 2-260C) **Package Construction Details** Assembly Site: AP3 Mold Compound: 1013422010 # Pins-Designator, Family: 100-ZWD, BGA Mount Compound: R008-0023A Solder Ball Composition: SnAgCu Bond Wire: 1.0 Mil Dia., Au **Qualification: Plan Test Results** Sample Size / Fail Reliability Test Conditions Lot 1 Lot 2 Lot 3 **T/C -55C/125C 77/0 77/0 77/0 -55C/+125C (700 Cyc) Ball Bond Shear 76 balls, 3 units min 76/0 76/0 76/0 76 balls, 3 units min 76/0 76/0 76/0 **Bond Pull** Notes: **Tests require preconditioning sequence: MSL2-260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com